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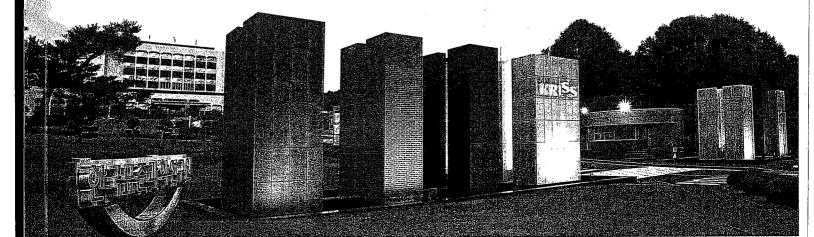
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International comparisons of optical fiber power measurements*

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We discuss the results of optical fiber power meter (OFPM) measurements at 1302 and 1546 nm made by NIST and six national measurement institutes (NMIs). We also describe transfer standards and the associated uncertainties. The comparisons show a reasonably good agreement between the participating laboratories, with relative differences that are within the standard (k=1) uncertainties.

INTRODUCTION

In our previous work we have reported international comparisons with several NMIs [1-5] for 1302 and 1546 nm. In this paper we present new measurement results from Centro Nacional de Metrología (CENAM-Mexico) and summarize previous fiber-based power measurements.

For OFPM calibrations, the NIST primary standard is the cryogenic radiometer, [6] which has an expanded measurement uncertainty of absolute optical power of 2 parts in 10⁴. NIST reference standards are calibrated against the primary standard by the use of collimated (free field) beams, but are typically used with divergent beams characteristic of laser light exiting an optical fiber.

TRANSFER STANDARDS

The transfer standards may be broadly described as "trap detectors" [7]. In the present case, our trap detectors, known as the "4×trap", are two Ge photodiodes and a spherical mirror. It has been shown in [8] that such a configuration provides a uniform response over a wide field of view and therefore requires no correction for beam geometry. This design increases the coupling efficiency for larger values of numerical apertures [9].

The trap detectors were calibrated at the participating laboratories against their reference standards at approximately 100 $\mu W,$ or -10 dBm.

We employed a direct-substitution method for the measurements. We used several Ge trap-based detectors in the comparisons. NIST's measurement system is described in detail in [10].

RESULTS

We present the results of the responsivity comparisons and their associated standard combined uncertainties (as error bars, k=1) in Fig. 1. The standard uncertainties for the optical power measurements were evaluated in accordance with the International Organization for Standardization Guide to the Expression of Uncertainty in Measurement [11]. Fig. 1 shows the relative difference (expressed in percent compared to the National Institute of Standards and Technology (NIST-USA) at two laser wavelengths of 1302 and 1546 nm among six NMIs: (1) National Physical Laboratory (NPL-UK), (2) All-Russian Research Optophysical Institute for Measurements (VNIIOFI-Russia), (3) Physikalisch-Technische Bundesanstalt (PTB-Germany), (4) the National Metrology Institute of Japan/National Institute of Advanced Industrial Science and Technology (NMIJ/AIST-Japan), (5) the Federal Office of Metrology (METAS-Switzerland), and (6) Centro Nacional de Metrología (CENAM-Mexico).

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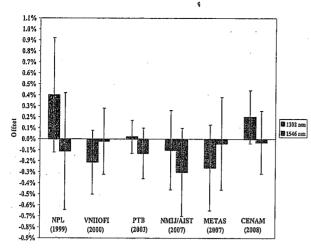


Figure 1. International comparison results (1999-2008; k=1)

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